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List of Patents and Publications for Applicant's

INFORMATION DISCLOSURE STATEMENT

(Use several sheets if necessary)

Applicant
Matthew A. Purdy

Filing Date:
August 4, 2003

Group:
2125

U.S. Patent Documents

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Foreign Patent Documents

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Other Art

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U.S. Patent Documents

| Exam. Init. | Ref. Des. | Document Number | Date | Name | Class | Sub Class | Filing Date of App. |
|-------------|-----------|-----------------|---------|-----------------------|-------|-----------|---------------------|
| CKB | A1 | 5,541,846 | 7/30/96 | Secrest | 364 | 468.17 | |
| CKB | A2 | 6,442,496 B1 | 8/27/02 | Pasadyn <i>et al.</i> | 702 | 83 | |
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| | A5 | | | | | | |

Foreign Patent Documents

| Exam. Init. | Ref. Des. | Document Number | Date | Country | Class | Sub Class | Translation Yes/No |
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| CKB | B1 | WO 02/23289 A2 | 3/21/02 | PCT | G05B | 13/02 | Yes |
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Other Art (Including Author, Title, Date Pertinent Pages, Etc.)

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| CKB | C1 | Williams <i>et al.</i> , "Optimized Sample Planning for Wafer Defect Inspection," IEEE, pp. 43-46, 1999 |
| | C2 | |
| | C3 | |

EXAMINER:

DATE CONSIDERED:

9/1/05

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